

Notice of References Cited	Application/Control No. 10/649,615		Applicant(s)/Patent Under Reexamination CHEN, CHRIS	
	Examiner Stephen G. Sherman		Art Unit 2674	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,195,016	02-2001	Shankle et al.	340/815.42
*	B	US-2002/0097216	07-2002	Chae, John Wook	345/108
*	C	US-6,633,276	10-2003	Jaynes, Paul Brian	345/158
*	D	US-4,459,587	07-1984	Leuthesser, Fred W.	340/815.6
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.